X-ray Photoelect	tron Spectroscopy	(In-house XPS, D	Pepth Profiling)
	Member	Status	
☐ Employee ☐		er	
	Nan	ne	
	Mobile N	lumber	
	Ema	ail	
	ID)	
	Sample Infor	mation (SI)	
*Sample Nam	۵۰		
* Submission	Date:		
* Sample Info	rmation:		
Sample Type	Sample Physical Prope	rties Sample Category	Sample Storage
Organic	Conductive	Non	Ambient
Inorganic	Semi Conductive	Hazardous	Refrigerator
Biological	Non	Radioactive	Freezer
Polymer/Composite	Other (Specify)	Carcinogenic	Light Sensitive
measurement • Yes (mples are not accepted, plea a. Are these samples magneti))		ole before
* Sample Info	rmation or Chemical Formul	a (Ex. Zn0:Ga/Al2O3) :	

* Analysis Element(s) (Ex. Zn, O, Ga, Al) :
* Number of Elements per Sample: Select how many elements you want to measure in one sample. 1-3 elements () 4 elements () 5 elements () 6 elements () 8 elements () 10 elements ()
* Size of Sample : Select your sample size. (LxWxH) in mm $< 3x \ 3x \ 2$ () $< 5x5x2$ () $< 10x10x2$ ()
* Ar+ Cleaning Select use Ar+ ions to perform surface etched or cleaning. • Yes () • NO ()
*Charge Compensation of Sample : Select charge compensation or not. • Yes () • NO ()
*Depth Profiling Perform depth profiling or not. • Yes () • NO need ()
*Thpe of Depth Profiling • Clusters Mode () • Mono Atomic ()
*Etching Time of Depth Profiling on Each Layer Select the etching time of each layer during the depth profiling. (Unit: Sec) • No Depth Profiling () • 30 () • 60 () • 90 () • 120 ()

*Message Please Noted Your Special Requirements Here (Ex. Sample Handling Condition, Different Return Address of Sample)
For Official Use Only
For Official Use Only: Sample received from (Institute Name)
Name:
rume.
Signature:
Signature:
Signature: Date: